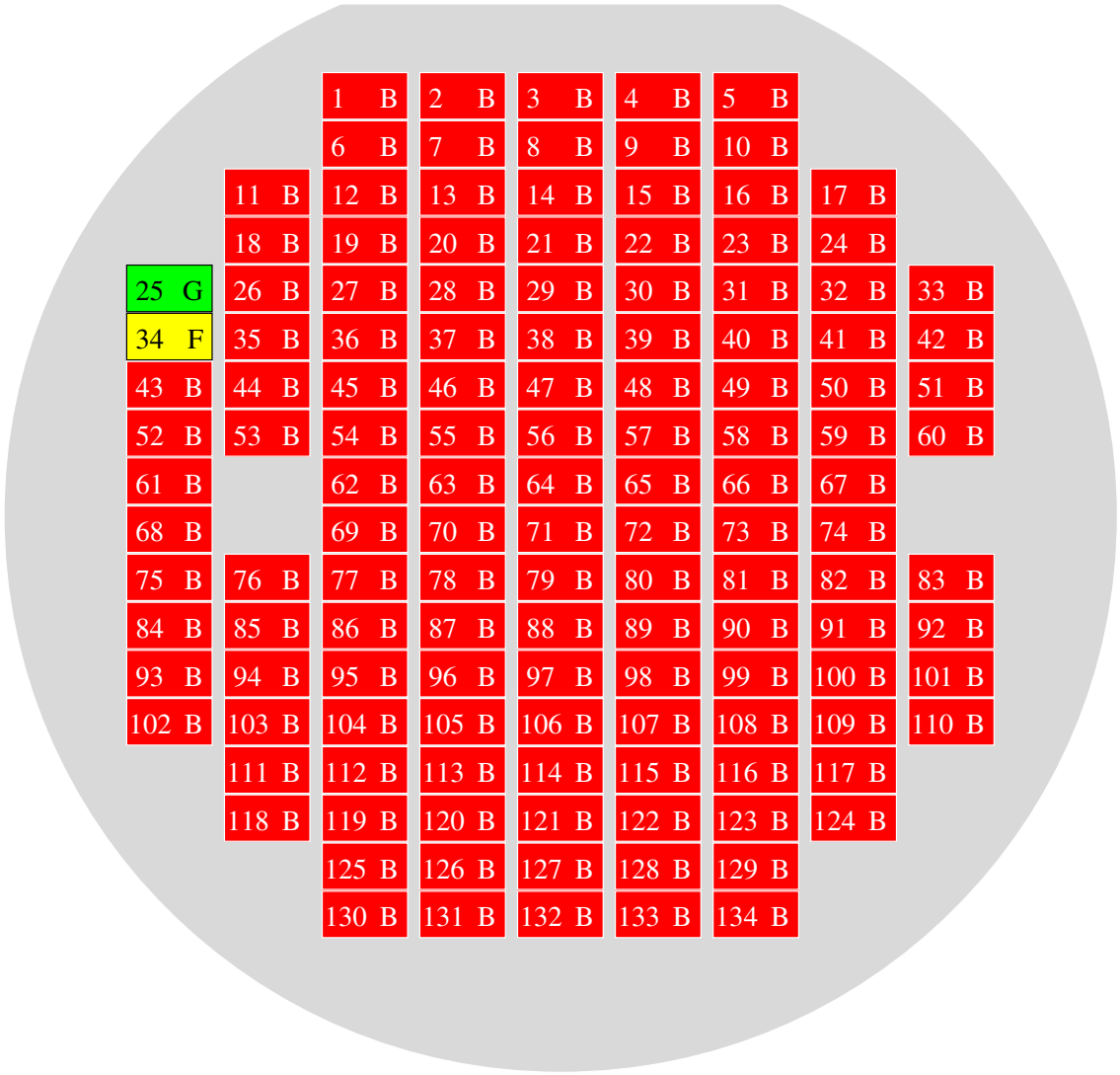
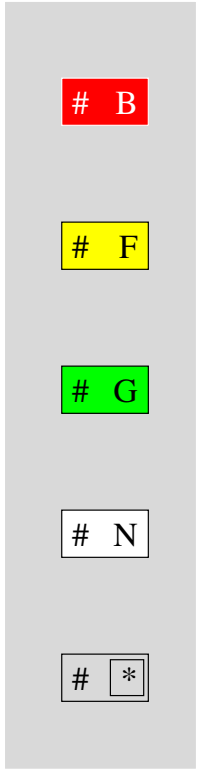
Die quality map for wafer 213 s/n: 21316-15-18

Date: 10/21/99





Bad die

Fair die

Good die

No info

Manually tagged